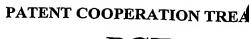
Translation





PCT

INTERNATIONAL PRELIMINARY EXAMINATION REPORT

(PCT Article 36 and Rule 70)

Applicant's or agent's file reference			· ·						
03NPCT003	FOR FURTHER A	TER ACTION See Notification of Transmittal of Internation Preliminary Examination Report (Form PCT/IPEA/4							
International application No. PCT/JP2003/014731	International filing da 19 November 20	te (day/month/year) 03 (19.11.2003)	Priority date (day/month/year)						
International Patent Classification (IPC) or no	ational classification an		20 November 2002 (20.11.2002)						
H01L 25/065, 25/07, 25/18, 23/1	2	d I C							
Applicant NEC CORPORATION									
	NEC CORP	ORATION							
 This international preliminary examination report has been prepared by this International Preliminary Examining Authority and is transmitted to the applicant according to Article 36. 									
This report is also accompanie	d hv ANNEYES ia a	haota eftil 1							
This report is also accompanied by ANNEXES, i.e., sheets of the description, claims and/or drawings which have been amended and are the basis for this report and/or sheets containing rectifications made before this Authority (see Rule 70.16 and Section 607 of the Administrative Instructions under the PCT).									
These annexes consist of a total of 6 sheets.									
3. This report contains indications relating to the following items:									
I Basis of the report	Parameter 1								
II Priority	•								
III Non-establishment of	opinion with regard to	novelty, inventive step	and industrial applicability						
IV Lack of unity of inven			·						
V Reasoned statement ur citations and explanati	ider Article 35(2) with ons supporting such sta	regard to novelty, inve	entive step or industrial applicability;						
VI Certain documents cite									
VII Certain defects in the in	nternational application	1							
VIII Certain observations on the international application									
Date of submission of the same									
Date of submission of the demand		Date of completion of t	his report						
19 November 2003 (19.11.2	(003)	28 Ju	ne 2004 (28.06.2004)						
Name and mailing address of the IPEA/JP		uthorized officer							
Facsimile No.	T.	elephone No.							
	''	orobitotic 140.							

Form PCT/IPEA/409 (cover sheet) (July 1998)

INTERNATIONAL PRELIMINARY EXAMINATION REPORT

International application No.

PCT/JP2003/014731

		of the re							
1.	With	regard to	the elements of the international application:*						
		the inte	rnational application as originally filed						
ì	\boxtimes	the desc	• •						
		pages	1-4, 7-18		, as originally filed				
		pages			, filed with the demand				
		pages	5-6 , filed with the	ne letter of	10 May 2004 (10.05.2004)				
	∇				2001 (20100,200)				
	\square	the clai							
		pages	1-3, 5	 	, as originally filed				
		pages	, as amer	ided (together with	any statement under Article 19				
ŀ		pages	4.60		, filed with the demand				
		pages	4, 6-8 , filed with the	ne letter of	10 May 2004 (10.05.2004)				
	\boxtimes	the drav	wings:						
ŀ		pages	1-29		, as originally filed				
		pages			, filed with the demand				
ŀ		pages	, filed with ti						
	Π.	ho nagua	nce listing part of the description:						
	ا		•		•				
		pages							
		pages			, filed with the demand				
		pages	, filed with the	e letter of					
2.	the in	iternatior	o the language, all the elements marked above were available or final application was filed, unless otherwise indicated under this item, its were available or furnished to this Authority in the following lang		nthority in the language in which which is:				
			guage of a translation furnished for the purposes of international sea	-					
	\sqcap	the language of publication of the international application (under Rule 48.3(b)).							
	Ħ		guage of the translation furnished for the purposes of international		mination (under Bulg 55.2 and/				
		or 55.3).						
3.	preli	regard to any nucleotide and/or amino acid sequence disclosed in the international application, the international ninary examination was carried out on the basis of the sequence listing:							
	H		ed in the international application in written form.						
	H	filed together with the international application in computer readable form. furnished subsequently to this Authority in written form.							
	H								
	furnished subsequently to this Authority in computer readable form.								
		The sta	ne statement that the subsequently furnished written sequence listing does not go beyond the disclosure in the ternational application as filed has been furnished.						
		The sta	atement that the information recorded in computer readable form rnished.	is identical to the	ne written sequence listing has				
4.		The am	endments have resulted in the cancellation of:						
			the description, pages						
			the claims, Nos.						
			the drawings, sheets/fig						
5.		This rep	oort has been established as if (some of) the amendments had not be the disclosure as filed, as indicated in the Supplemental Box (Rule	een made, since to	hey have been considered to go				
*	Repla in thi and 7	s report	heets which have been furnished to the receiving Office in respons as "originally filed" and are not annexed to this report since	e to an invitation to they do not cor	under Article 14 are referred to ntain amendments (Rule 70.16				
**	** Any replacement sheet containing such amendments must be referred to under item 1 and annexed to this report.								

 Reasoned statement under Article 35(2) with regard to novelty, inventive step or industrial applicability; citations and explanations supporting such statement 					
. Statement					
Novelty (N)	Claims	1-8	YES		
	Claims		NO		
Inventive step (IS)	Claims	4,7	YES.		
	Claims	1-3, 5, 6, 8	NO		
Industrial applicability (IA)	Claims	1-8	YES		
	Claims		NO		

2. Citations and explanations

Claims 1 and 8

Document 1: JP, 8-340021, A (Hitachi, Ltd.), 24 December, 1996 (24.12.96), [0030]-[0045], [0058], [0059], [Fig. 14]

describes (A) an electronic part having (1) a semiconductor device with plural electrodes formed on a circuit face and (2) a flexible substrate (a) having (i) a wiring pattern and (ii) a polyimide film(s) on one face or both faces of the wiring pattern, and (b) bent around the semiconductor device, in which the flexible substrate has (1) a first electrode (a) provided on the face of the semiconductor device side, (b) connected with the device-side electrodes of the semiconductor device and (c) sealed by a thermoplastic insulation layer, and (2) a second electrode provided on the face different from the face provided with the first electrode, and the flexible substrate also has plural wiring pattern layers formed on it; and (B) that the electronic parts, each obtained as described above, are laminated.

Using a thermoplastic polyimide film is a well-known technical matter in the technical field of electronic parts. So, using a thermoplastic polyimide as the polyimide film described in document 1 is considered to be a matter obvious to a person skilled in the art.

Claims 2 and 8

Document 2: JP, 8-335663, A (Sony Corp.), 17 December, 1996 (17.12.96), [0031]-[0033], [0046] describes a technique in which a groove is formed in a bent portion of a flexible rewiring film provided around a bare chip.

It is considered to be a matter obvious for a person skilled in the art to apply the technique described in document 2 in which a groove is formed in a bent portion, to the bent portion of the flexible film described in document 1.

Claims 3, 5 and 8

Document 3: JP, 2001-308261, A (Seiko Epson Corp.), 2 November, 2001 (02.11.01), [0012]-[0028] describes a technique in which (1) a cavity is formed in a flexible substrate, and (2) a semiconductor device is accommodated in the cavity.

Juxtaposing the inventions described in documents 1-3 as required is considered to be a matter obvious to a person skilled in the art.

INTERNATIONAL PRESIMINARY EXAMINATION REPORT

Interior No.
PCT/JP03/14731

Supplemental Box

(To be used when the space in any of the preceding boxes is not sufficient)

Continuation of: V.2

Claims 4 and 7

The documents cited in the ISR neither describe nor suggest the constitution in which a flexible substrate is bent around a semiconductor device, wherein the flexible substrate has (1) a first electrode (a) provided on the face of the semiconductor device side, (b) connected with the device-side electrodes of the semiconductor device, and (c) sealed by a thermoplastic insulating material, and (2) a second electrode provided on the face device accommodated with the first electrode, and the flexible substrate also has a semiconductor device accommodated in the depression formed in a region where the bent flexible substrate is directly connected with itself.

Claims 6 and 8

Document 1 describes a multi-chip semiconductor device which has (1) a semiconductor device with one or plural electrodes formed on a circuit face and (2) a flexible substrate (a) having (i) a wiring pattern and (ii) a polyimide film(s) provided on one face or both faces of the wiring pattern and (b) bent around the semiconductor device, wherein the flexible substrate has (1) a first electrode (a) provided on the face of the semiconductor device side, (b) connected with the device-side electrodes of the semiconductor device and (c) sealed by a thermoplastic insulating material, and (2) a second electrode provided on the face different from the face provided with the first electrode, and the flexible substrate also has a region where the bent flexible substrate is directly connected with itself.

Using a thermoplastic polyimide film is a well-known technical matter in the technical field of electronic parts. So, using a thermoplastic polyimide as the polyimide film described in document 1 is considered to be a matter obvious to a person skilled in the art.